

30V N-Channel Enhancement Mode MOSFET

Description

The AP3414MI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 30V$ $I_D = 18A$

$R_{DS(ON)} < 12m\Omega$ @ $V_{GS}=10V$ (Type: 9.0m Ω)

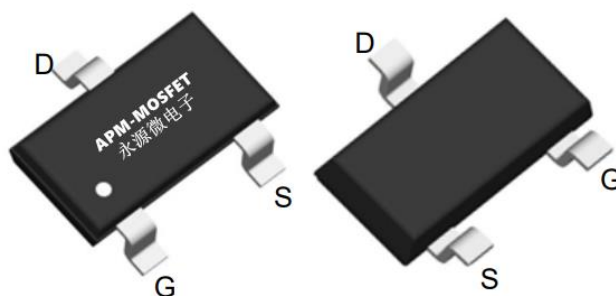
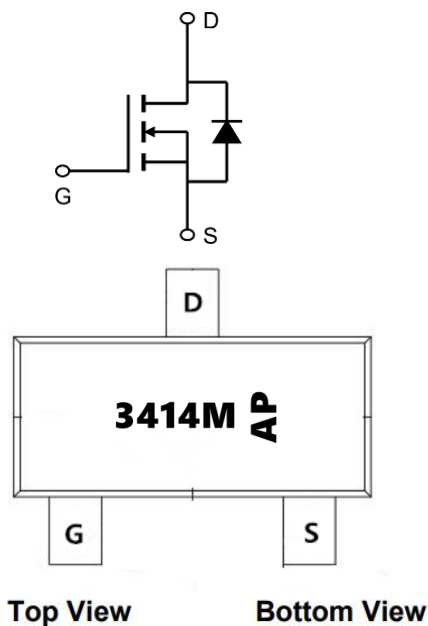
$R_{DS(ON)} < 13m\Omega$ @ $V_{GS}=10V$ (Type: 11m Ω)

Application

VBUS

Wireless impact

Mobile phone fast charging



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP3414MI	SOT23-3L	3414M AP	5000

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	18	A
$I_D @ T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	9	A
I_{DM}	Pulsed Drain Current ²	54	A
$P_D @ T_C=25^\circ\text{C}$	Total Power Dissipation ⁴	29	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹	125	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	4.32	$^\circ\text{C/W}$

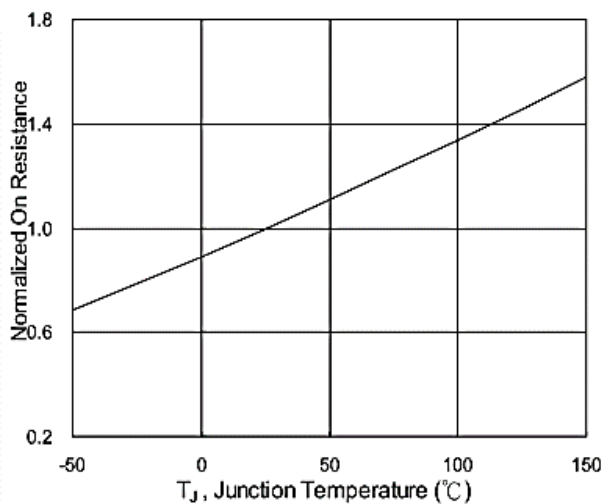
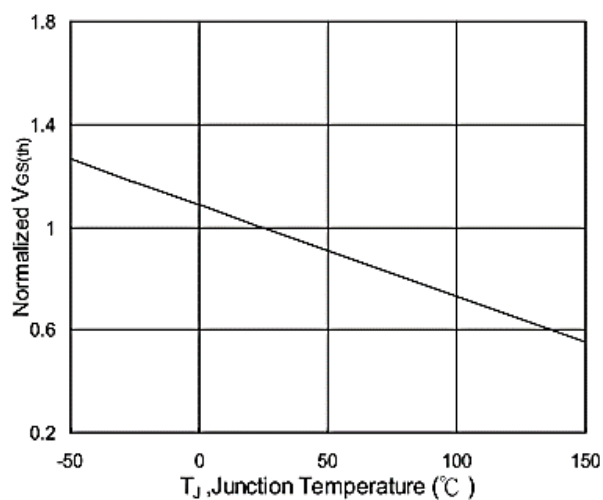
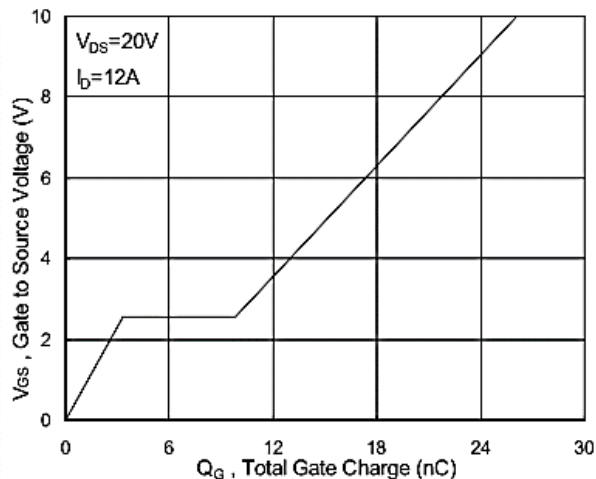
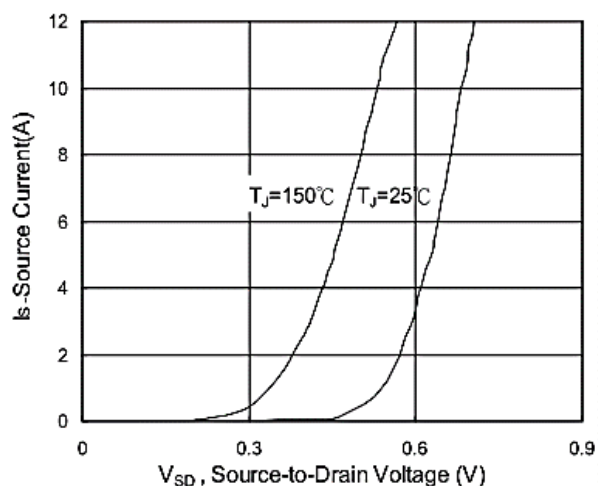
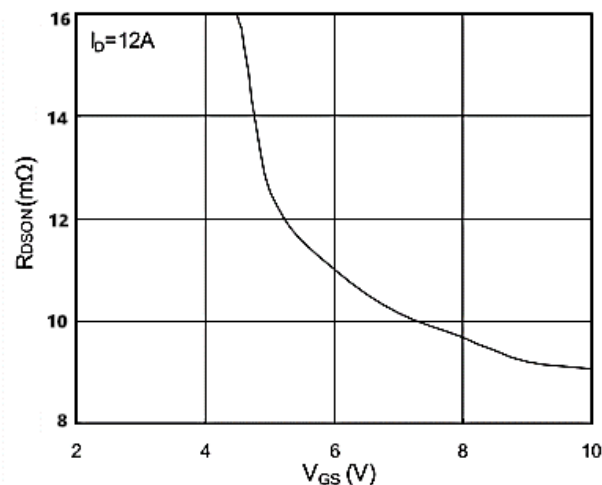
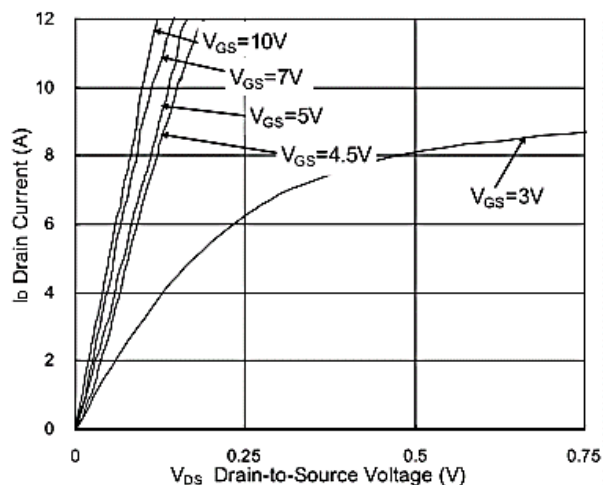
30V N-Channel Enhancement Mode MOSFET
Electrical Characteristics ($T_c=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0V$, $I_D=250\mu A$	30	33	---	V
RDS(ON)	Static Drain-Source On-Resistance ²	$V_{GS}=10V$, $I_D=12A$	---	9.0	12	m Ω
		$V_{GS}=4.5V$, $I_D=10A$	---	11	13	
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=250\mu A$	1.0	1.6	2.5	V
$\Delta V_{GS}(th)$	$V_{GS}(th)$ Temperature Coefficient		---	-5.8	---	mV/ $^{\circ}\text{C}$
IDSS	Drain-Source Leakage Current	$V_{DS}=24V$, $V_{GS}=0V$, $T_J=25^{\circ}\text{C}$	---	---	1	μA
		$V_{DS}=24V$, $V_{GS}=0V$, $T_J=55^{\circ}\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, $V_{DS}=0V$	---	---	± 100	nA
gfs	Forward Transconductance	$V_{DS}=5V$, $I_D=15A$	---	9.8	---	S
R_g	Gate Resistance	$V_{DS}=0V$, $V_{GS}=0V$, $f=1\text{MHz}$	---	1.7	---	Ω
Q_g	Total Gate Charge (4.5V)	$V_{DS}=20V$, $V_{GS}=4.5V$, $I_D=12A$	---	12.8	---	nC
Q_{gs}	Gate-Source Charge		---	3.3	---	
Q_{gd}	Gate-Drain Charge		---	6.5	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=12V$, $V_{GS}=10V$, $R_G=3.3\Omega$, $I_D=5A$	---	4.5	---	ns
T_r	Rise Time		---	10.8	---	
$T_{d(off)}$	Turn-Off Delay Time		---	25.5	---	
T_f	Fall Time		---	9.6	---	
C_{iss}	Input Capacitance	$V_{DS}=15V$, $V_{GS}=0V$, $f=1\text{MHz}$	---	1317	---	pF
C_{oss}	Output Capacitance		---	163	---	
C_{rss}	Reverse Transfer Capacitance		---	131	---	
IS	Continuous Source Current ^{1,6}	$V_G=V_D=0V$, Force Current	---	---	46	A
ISM	Pulsed Source Current ^{2,6}		---	---	92	A
VSD	Diode Forward Voltage ²	$V_{GS}=0V$, $I_S=1A$, $T_J=25^{\circ}\text{C}$	---	---	1	V

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3、The power dissipation is limited by 150°C junction temperature
- 4、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics



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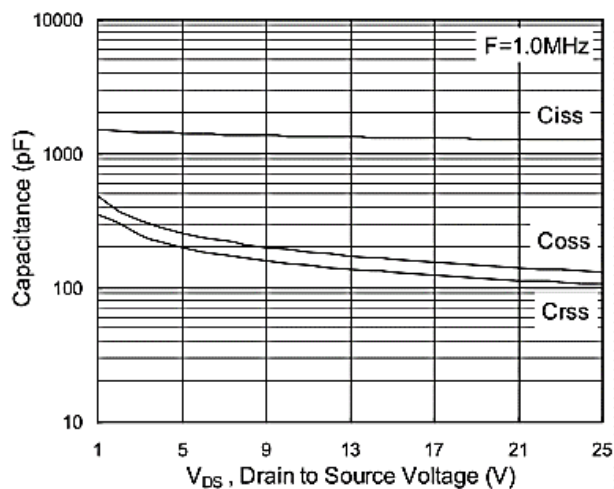


Fig.7 Capacitance

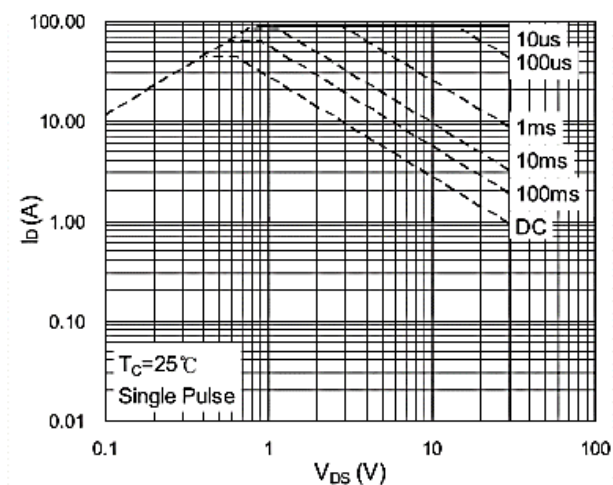


Fig.8 Safe Operating Area

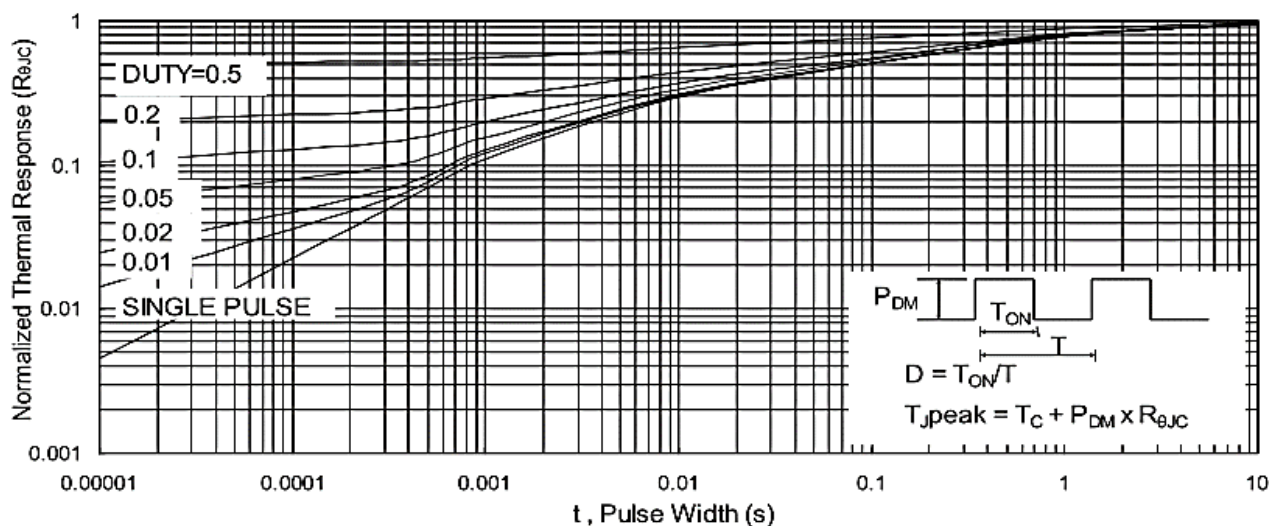


Fig.9 Normalized Maximum Transient Thermal Impedance

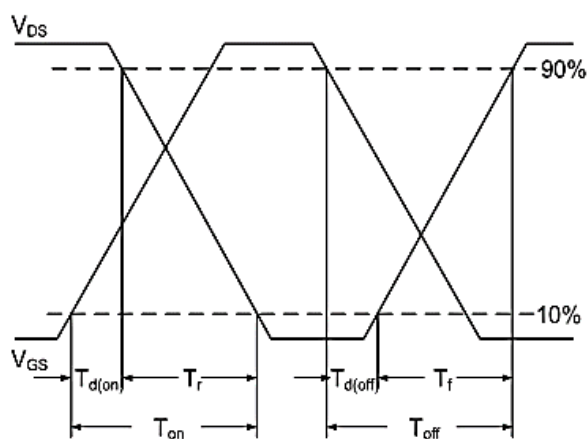


Fig.10 Switching Time Waveform

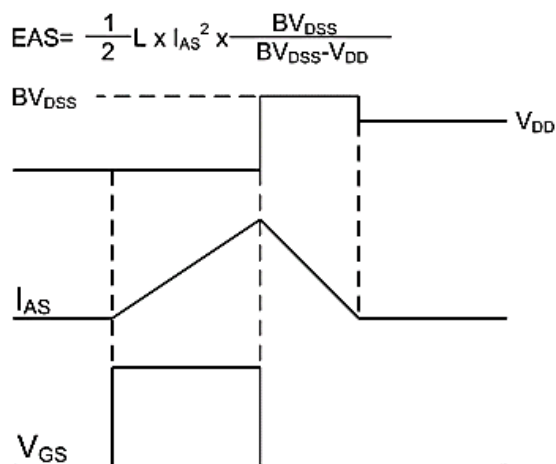
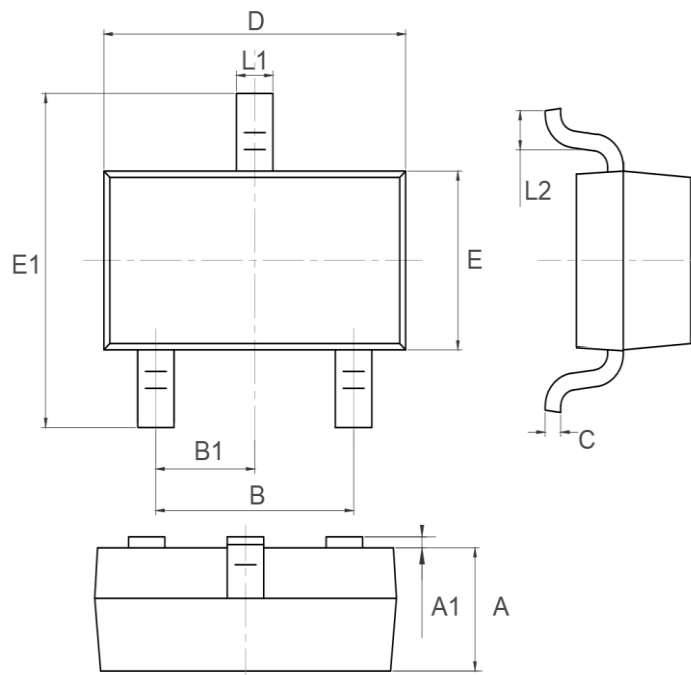


Fig.11 Unclamped Inductive Switching Waveform

Package Mechanical Data-SOT23-3L-Single



Symbol	Dim in mm		
	Min	Typ	Max
A	1	1.1	1.2
A1	0	0.05	0.1
B	1.8	1.9	2
B1	0.95TYP		
C	0.1	0.15	0.2
D	2.82	2.92	3.02
E	1.5	1.6	1.7
E1	2.65	2.8	2.95
L1	0.3	0.4	0.5
L2	0.3	0.45	0.6

30V N-Channel Enhancement Mode MOSFET**Attention**

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Edition	Date	Change
REV1.0	2023/10/10	Initial release

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